Intelligent Electronic Monitoring Systems and Their Application

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Message from the Guest Editors

Dear Colleagues,

This Special Issue of the journal will publish articles relating to intelligent electronic systems. Electronic systems are widely used in various fields when it is necessary to monitor various parameters. Electronic systems can be designed and manufactured based on PCBs and microcontrollers. In order for the electronics monitoring system to work, it is necessary to create an original software code for its management. This field includes various disciplines such as programming, digital electronics, automatic control, physics, telecommunications, etc. The intended scope of the Special Issue covers areas such as computer science, data electronic monitoring systems, the application of digital electronics, the development of control applications, etc.

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Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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